

FREE SEMINAR ORGANIZED BY WINTECH-NANO
4 NOVEMBER, 2008, TUESDAY
06:00 PM – 09:30 PM

WinTech-Nano is organizing a free 3-hour seminar on FA lab Services. WinTech-Nano is the largest independent FA lab that serving wafer fab, IC design house and hard disc indu e services like FIB/TEM/Auger/SIMS. All participants will be given a high quality training session on advance Failure stry. We provide advanc Analysis free of charge. Buffet dinner will be provided as well. The seminar will feature number of distinguished speakers in the FA lab services. Please contact the organizer, for more details/registration on this seminar.

WinTech-Nano Technology Services Pte Ltd
10 Science Park Road, #03-26 The Alpha
Singapore Science Park II, Singapore 117684

Contact Person: Fu Chao
Designation: Manager, Marketing
Tel: (65) 6777 7354
Fax: (65) 6777 2462
Email: fuchao@wintech-nano.com
Website: www.wintech-nano.com

About WinTech Nano

WinTech is a young and dynamic organization that is at breadth with the latest cutting-edge technology and development for the Industry. Our technical specialists are well trained with years of experience and are committed to work confidentially with you to satisfy all requirements. We are proud to be your one-stop lab service provider. Our services are highly professional yet affordable; our analyses are first class yet have the shortest turnaround time in town.

Failure Analysis Services

At WinTech Nano, we diagnose the IC failures you encounter during your product development and high volume manufacturing stages by conducting microstructure analysis at the specific failure locations. With our strong expertise in Failure Analysis and “can do” attitude, our staff are committed to deliver our highest analysis to your satisfaction.

- [Decapsulation](#)
- [Fault Isolation](#)
- [SEM \(Scanning Electron Microscope\)](#)
- [FIB Cross-section](#)
- [TEM \(Transmission Electron Microscope\)](#)

IC Circuit Edit Services

IC Circuit edit is an important tool for IC designers to achieve fast and reliable circuit verification result. Circuit edit services are done in the FIB (Focused Ion Beam). FIB with certain GIS (Gas Injection System) sources, ion beam etching speed against certain materials will be accelerated tens of times. WinTech Nano offers two types of Circuit Edit services: Circuit Modification & Signal Tap-out. We are able to perform circuit edit on decapsulated die or singulated die. WinTech Nano has experience over 1000 circuit edit cases with whole range of:

- [Circuit Modification](#)
- [Signal Tap-out](#)

Material Analysis Services

Surface analysis is applied to characterize the outer few atomic layers of a solid surface. Surface analysis is conducted to reveal properties such as morphology, crystal structure, adhesion, thickness, chemical activity, stress, wettability, distribution profiles, bio-compatibility. These techniques are commonly utilized to analyzed surface defects at sub-micron and nanometer scales. Combined with FIB's precise locating and cross-sectioning capability, the application of surface analysis are well-extended to 3D materials analysis, serving a wide range of industries such as Semiconductor, Data Storage, Thin Film, Polymer and Nano Technology.

At WinTech, our staff specialized in a variety of surface analysis techniques. We offer professional analytical services on various application. Based on the information you need, we can recommend the best analytical technique for your specific purposes. Our specialists will work with you in a completely confidential way to provide the analytical solution to your expectations.

- [AES - Auger Electron Spectroscopy](#)
- [EDX- SEM; EDX-TEM](#)
- [AFM - Atomic Force Microscopy](#)
- [FTIR - Fourier Transform InfraRed Spectroscopy](#)
- [SIMS-Secondary Ion Mass Spectrometry](#)
- [XPS- X-ray Photoelectron Spectroscopy](#)
- [SRP - Spreading Resistance Profilometry](#)